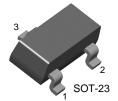
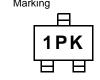


## MMBT2222AK

# **NPN Epitaxial Silicon Transistor**

## **General Purpose Transistor**





1. Base 2. Emitter 3. Collector

## **Absolute Maximum Ratings** T<sub>a</sub> = 25°C unless otherwise noted

Symbol	Parameter	Value	Units
$V_{CBO}$	Collector-Base Voltage	75	V
V <sub>CEO</sub>	Collector-Emitter Voltage	40	V
V <sub>EBO</sub>	Emitter-Base Voltage	6	V
I <sub>C</sub>	Collector Current	600	mA
P <sub>C</sub>	Collector Power Dissipation	350	mW
T <sub>STG</sub>	Storage Temperature	150	°C

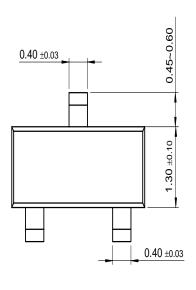
## **Electrical Characteristics** $T_a$ =25°C unless otherwise noted

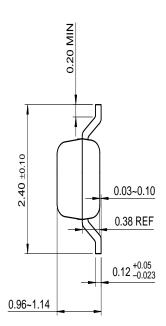
Symbol	Parameter	Test Condition	Min.	Max.	Units
BV <sub>CBO</sub>	Collector-Base Breakdown Voltage	$I_C = 10\mu A, I_E = 0$	75		V
BV <sub>CEO</sub>	Collector-Emitter Breakdown Voltage	$I_C = 10 \text{mA}, I_B = 0$	40		V
BV <sub>EBO</sub>	Emitter-Base Breakdown Voltage	$I_E = 10\mu A, I_C = 0$	6		V
I <sub>CBO</sub>	Collector Cut-off Current	V <sub>CB</sub> = 60V, I <sub>E</sub> = 0		0.01	μΑ
h <sub>FE</sub>	DC Current Gain *	$V_{CE} = 10V, I_C = 0.1mA$ $V_{CE} = 10V, I_C = 1mA$ $V_{CE} = 10V, I_C = 10mA$ $V_{CE} = 10V, I_C = 150mA$ $V_{CE} = 10V, I_C = 500mA$	35 50 75 100 40	300	
V <sub>CE</sub> (sat)	Collector-Emitter Saturation Voltage *	$I_C = 150 \text{mA}, I_B = 15 \text{mA}$ $I_C = 500 \text{mA}, I_B = 50 \text{mA}$		0.3 1.0	V V
V <sub>BE</sub> (sat)	Base-Emitter Saturation Voltage *	$I_C = 150 \text{mA}, I_B = 15 \text{mA}$ $I_C = 500 \text{mA}, I_B = 50 \text{mA}$	0.6	1.2 2.0	V V
f <sub>T</sub>	Current Gain Bandwidth Product	I <sub>C</sub> = 20mA, V <sub>CE</sub> = 20V, f = 100MHz	300		MHz
C <sub>ob</sub>	Output Capacitance	V <sub>CB</sub> = 10V, I <sub>E</sub> = 0, f = 1MHz		8	pF
NF	Noise Figure	$I_C = 100\mu A$ , $V_{CE} = 10V$ $R_S = 1K\Omega$ , $f = 1MHz$		4	dB
t <sub>ON</sub>	Turn On Time	$V_{CC} = 30V, I_C = 150mA$ 35 $V_{BE} = 0.5V, I_{B1} = 15mA$		35	ns
t <sub>OFF</sub>	Turn Off Time	$V_{CC} = 30V, I_C = 150mA,$ 285 $I_{B1} = I_{B2} = 15mA$		ns	

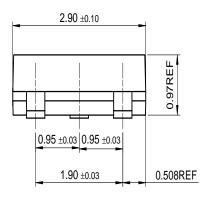
<sup>\*</sup> Pulse Test: Pulse Width≤300µs, Duty Cycle≤2%

## **Mechanical Dimensions**

# SOT-23







Dimensions in Millimeters

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FACT Quiet Series™		OCXPro™	RapidConnect™	UHC™
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